

FORM PTO - 1449

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

ATTORNEY DOCKET NO.: DPL-043

APPLICANT(S): Williams et al.

SERIAL NO.: 10/723,332

FILING DATE: November 26, 2003

CONFIRMATION NO: 9485

GROUP: 2859

U.S. PATENT DOCUMENTS EXAM. DOCUMENT DATE NAME CLASS SUB FILING DATE IF APPROPRIATE INIT. NUMBER CLASS 73 A21 4,561,286 12/31/85 Sekler et al. 6/28/84 A22 5,476,002 12/19/95 Bowers et al. 73 24.01 5/5/94 6,370,955 B1 4/16/02 Tuller et al. 73 579 11/29/99 A23 FOREIGN PATENT DOCUMENTS DOCUMENT DATE COUNTRY CLASS SUB FILING **ABSTRACT ENGLISH** EXAM. CODE INIT. NUMBER DATE ONLY **CLASS** LANG (Y/N) 1034475 GB 3/26/64 N Υ Βl 6/29/66 4/5/01 -B2 01/77624 A2 10/18/01 PCT N OTHER ART, JOURNAL ARTICLES, ETC. EXAM. OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication) INIT. Copy of International Search Report, PCT/US 03/38300, Mailing Date May 27, 2004. DATE CONSIDERED **EXAMINER**

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APPLICANT(S): Williams et al.

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U.S. PATENT DOCUMENTS

EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
a	AI	4,783,174	11/08/88	Gmelin et al.	374	33	08/18/86
1	A2	5,165,792	11/24/92	Crowe et al.	374	10	03/01/91
	A3	5,212,988	5/25/93	White et al.	73	599	10/10/91
- .	A4	5,288,147	02/22/94	Schaefer et al.	. 374	10	11/09/92
	A5	5,416,322	5/16/95	Chace et al.	250	288	04/21/94
	A6	5,842,788	12/01/98	Danley et al.	374	12	10/31/97
	A7	6,079,873	06/27/00	Cavicchi et al.	374	10	06/30/98
	A8	6,106,149	08/22/00	Smith	374	31	12/02/98
	A9	6,189,367	02/20/01	Smith et al.	73	19.03	12/02/98
	A10	6,190,035	02/20/01	Smith	374	31	05/26/00
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	A12	6,354,732	03/12/02	Casati et al.	374	14	07/18/00
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	A16	2001/0008081	07/19/01	Smith et al.	73	19.03	02/16/01
	A17	2001/0012312	08/09/01	Smith	374	31	01/23/01
	A18	2002/0003830	01/10/02	Tanaka et al.	374	31	01/12/01
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EXAM. INIT.	1	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	FILING DATE	ABSTRACT ONLY	ENGLISH LANG (Y/N)



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10/18/09

		OTHER ART, JOURNAL ARTICLES, ETC.		
EXAM. INIT.	OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)			
av	CI	RJ LEE microsytems™, NanoScale 9100™ User's Manual. Lo dale		
	C2	SAW Sensor Seminar, Helsinki University of Technology (HUT), Material Physics Lab (May 2002).		
	C3	TA Instruments "Modulated Thermogravimetric Analysisis: A new approach for obtaining kinetic parameters." ho dake		
	C4	TA Instruments brochure TGA 2050 Thermogravimetric Analyzer. ho dake		
1	C5	TA Instruments, "Thermogravimetric Analysis" (TGA)," slide presentation. his dake		